

<b>Notice of References Cited</b>	Application/Control No. 10/766,466	Applicant(s)/Patent Under Reexamination CHIOLA ET AL.	
	Examiner Thien F. Tran	Art Unit 2811	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2004/0061195	04-2004	Okada et al.	257/477
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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